

Search Notes



Application/Control No.

09/866,334

Examiner

Hiep Nguyen

Applicant(s)/Patent under Reexamination

EMBABI ET AL.

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
327	308	01-20-05	Nh
333	81.R	-	Nh
	101	-	
updated March		07.11.05	Nh
327	307	-	-
	308	-	-

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST	01.20.05	Nh
EAST	07.11.05	Nh
see attachment		